

IEC/TR 61869-103

Edition 1.0 2012-05

TECHNICAL REPORT



Instrument transformers – The use of instrument transformers for power quality measurement





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

INSTRUMENT TRANSFORMERS – THE USE OF INSTRUMENT TRANSFORMERS FOR POWER QUALITY MEASUREMENT

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IEC 61869-103, which is a technical report, has been prepared by IEC technical committee 38: Instrument transformers.

The text of this technical report is based on the following documents:

Enquiry draft	Report on voting
38/402/DTR	38/409/RVC

Full information on the voting for the approval of this technical report can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 61869 series, published under the general title *Instrument transformers*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability dateindicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

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INSTRUMENT TRANSFORMERS – THE USE OF INSTRUMENT TRANSFORMERS FOR POWER QUALITY MEASUREMENT

1 Scope

This part of IEC 61869 is applicable to inductive and electronic instrument transformers with analogue or digital output for use with electrical measuring instruments for measurement and interpretation of results for power quality parameters in 50/60 Hz a.c. power supply systems.

This part of IEC 61869 aims at giving guidance in the usage of HV instrument transformers for measuring power quality parameters.

The power quality parameters considered in this document are power frequency, magnitude of the supply voltage and current, flicker, supply voltage dips and swells, voltage interruptions, transient voltages, supply voltage unbalance, voltage and current harmonics and interharmonics, mains signalling on the supply voltage and rapid voltage changes.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60044-8:2002, Instrument transformers – Part 8: Instrument transformers: Electronic current transformers

IEC 61000-2-1:1990, Electromagnetic compatibility (EMC) – Part 2-1: Environment – Description of the environment – Electromagnetic environment for low-frequency conducted disturbances and signalling in public power supply systems

IEC 61000-2-2:2002, Electromagnetic compatibility (EMC) – Part 2-2: Environment – Compatibility for low frequency conducted disturbances and signalling in public low-voltage power supply systems

IEC 61000-4-7:2002, Electromagnetic compatibility (EMC) – Part 4-7: Testing and measurement techniques – General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto

IEC 61000-4-15:2010, Electromagnetic compatibility (EMC) – Part 4-15: Testing and measuring techniques – Flickermeter – Functional and design specifications

IEC 61000-4-30:2008, Electromagnetic compatibility (EMC) – Part 4-30: Testing and measurement techniques – Power quality measurement methods

IEC 60359:2001, Electrical and electronic measurement equipment – Expression of performance

IEC 61557-12:2007, Electrical safety in low voltage distribution systems up to 1 000 V a.c. and 1 500 V d.c. – Equipment for testing, measuring or monitoring of protective measures – Part 12: Performance measuring and monitoring devices (PMD)

EN 50160:2007, Voltage characteristics of electricity supplied by public distribution networks

3 Terms and definitions

For the purpose of this document, the terms and definitions given in IEC 61000-4-30:2008 and the following apply.

3.1

dip threshold

voltage magnitude specified for the purpose of detecting the start and the end of a voltage dip

3.2

flicker

impression of unsteadiness of visual sensation induced by a light stimulus whose luminance or spectral distribution fluctuates with time

[SOURCE: IEC 60050-161:1990, 161-08-13]

3.3

fundamental component

component whose frequency is the fundamental frequency

[SOURCE: IEC 60050-101:1998, 101-14-49, modified definition]

3.4

fundamental frequency

frequency in the spectrum obtained from a Fourier transform of a time function, to which all the frequencies of the spectrum are referred

[SOURCE: IEC 60050-101:1998, 101-14-50, modified definition]

Note 1 to entry: In case of any remaining risk of ambiguity, the fundamental frequency may be derived from the number of poles and speed of rotation of the synchronous generator(s) feeding the system.

3.5

harmonic component

any of the components having a harmonic frequency

[SOURCE: IEC 61000-2-2:2002, definition 3.2.4]

Note 1 to entry: Its value is normally expressed as an r.m.s. value. For brevity, such a component may be referred to simply as an harmonic.

3.6

harmonic frequency

frequency which is an integer multiple of the fundamental frequency

Note 1 to entry: The ratio of the harmonic frequency to the fundamental frequency is the harmonic order (recommended notation: n) (IEC 61000 2-2, definition 3.2.3).

3.7

influence quantity

quantity which is not the subject of the measurement and whose change affects the relationship between the indication and the result of the measurement

[SOURCE: IEC 60050-311:2001, 311-06-01]

Note 1 to entry: This quantity is generally external to the measurement equipment.

3.8

interharmonic component

component having an interharmonic frequency